

**METHOD AND APPARATUS FOR THREE DIMENSIONAL INSPECTION OF  
ELECTRONIC COMPONENTS**

**ABSTRACT OF THE DISCLOSURE**

An apparatus for three dimensional inspection of an  
5 electronic part which has a camera and illuminator for  
imaging a first view of the electronic part. An optical  
element is positioned to reflect a different view of the  
electronic part into the camera, and the camera thus  
provides an image of the electronic part having differing  
10 views of the electronic part. An image processor applies  
calculations on the differing views to calculate a three  
dimensional position of at least one portion of the  
electronic part.